

DLD 3636



Standard Delayline Detector for
Photoemission Electronmicroscops
(PEEM)

Features



- CF63 mounting flange
 - 36 x 36 mm² active area of DLD body and \varnothing 40 mm active MCP area
 - Linear response due to single event counting
 - Extremely low dark count rate: < 5 cps
 - Up to 3 MHz count rate in 2D mode
 - Up to 41 μ m of pixel size
 - Up to 81 ps digital time bin resolution
 - Time histogramming for time of flight (tof) measurements
 - Also available as hybrid version with an additional integrated 9 channel detector
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- For further information contact
Surface Concept GmbH